

# Search Notes



Application No.

09/484,721

Examiner

Tan Dean D. Nguyen

Applicant(s)

YOKOYAMA, KOZO

Art Unit

3629

## SEARCHED

Class	Subclass	Date	Examiner
		9/26/02	
1 364	550	7/20/03	on
2 340	825.52	5/15/04	
	286.01		
	270.00		
	735		
	736		
3 345	718°		
	736 <sup>x</sup>		
	771 <sup>x</sup>		
4 700	19		
	286		
	updating	5/15/04	
	Updating	10/26/04	✓

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
1 345	770	10/26/04	on
	735		
	736		
2 340	825.52		
	286.01		
	770.00		
	735		
	736		
3 700	19, 286		

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Inventor name search	9/29/02	BG
EAST	9/29/02	DN
(US, EP, JP, Derwent, IBM)		
Dialog		
1) Updating	7/20/03	on
2) Updating	5/15/04	
3) Updating	10/26/04	
Reviewing w/ Primary Examiners		
1. Trieu, Van AU 2636	Class	
2. Zimmerman	340	
3. Thompson,	(709)	
4. Baderman	(714)	
5. Perveen, Rehana	(713)	φ-search
6. Bayerl, Raymond	(340)	9/04
(AU 2173)		
7. Huynh, Ba	(340)	10/04
(H+B) 2173		
	10/04	

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SEARCHED			
Class	Sub.	Date	Exmr.
364	550		
340	825.52 <sup>x</sup> <del>870.03</del> <del>286.01</del>	7/26/02	BDP
updating		7/20/03	DM
340	770° 735 <sup>x</sup> 736 <sup>x</sup>	5/25/04	DM

INTERFERENCE SEARCHED			
Class	Sub.	Date	Exmr.

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	Date	Exmr.
1. number None Search	7/24/02	BDP
East Search (US, EPO, JPO, IBM Nexus)	7/24-26/02	BDP
Dialog Search	9/24/02	BDP
updating	7/20/03	DM
1. Reviewing w/ Trieu, Van AU 2636		primary examiner
2. Zimmerman	(340)	5/26/04
3. Thompson	(709)	↓
4. Baderman	(714)	↓
5. Perveen, Lahana <u>No search</u>	(710) (713)	5/26/04 ✓
6. BAYERL, Raymond • AU 2173	(340)	5/27/04